

## Publication

Atomic force microscopy : general aspects and application to insulators

### **JournalArticle (Originalarbeit in einer wissenschaftlichen Zeitschrift)**

**ID** 171290

**Author(s)** HEINZELMANN, H; MEYER, E; GRUTTER, P; HIDBER, HR; ROSENTHALER, L; GUN-THERODT, HJ

**Author(s) at UniBasel** Meyer, Ernst ;

**Year** 1988

**Title** Atomic force microscopy : general aspects and application to insulators

**Journal** Journal of vacuum science & technology. A, Vacuum, surfaces and films

**Volume** 6

**Number** 2

**Pages / Article-Number** 275-278

**Publisher** American Vacuum Society

**ISSN/ISBN** 0734-2101

**edoc-URL** <http://edoc.unibas.ch/dok/A5262173>

**Full Text on edoc** No;

**Digital Object Identifier DOI** 10.1116/1.575424

**ISI-Number** WOS:A1988M650200020

**Document type (ISI)** Article